


<b>Search Notes</b>  	<b>Application/Control No.</b>  10672010	<b>Applicant(s)/Patent Under Reexamination</b>  SHIBUYA ET AL.
	<b>Examiner</b>  ALEX LIEW	<b>Art Unit</b>  2624

SEARCHED			
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SEARCH NOTES		
Search Notes	Date	Examiner
382/141-152, 181-231 limited to text search	1/1/09	AL

INTERFERENCE SEARCH			
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